



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 292393US2PCT		SERIAL NO. 10/582,791	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Laurent PAIN			
				FILING DATE June 14, 2006		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/BT/	AA	2003 039923	02-27-03	MANGAT, Pawitter et al.			
	AB	6 596 465	07-22-03	MANGAT, Pawitter Jit Singh et al.			
	AC	2003 027053	02-06-03	YAN, Pei-yang			
	AD	2002 122995	09-05-02	MANCINI, David P. et al.			
	AE	5 945 238	08-31-99	HUGGINS, Alan H. et al.			
	AF	5 985 518	11-16-99	HUGGINS, Alan H. et al.			
/BT/	AG	5 953 577	09-14-99	HUGGINS, Alan H. et al.			
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/BT/	AO	60 142518	12-03-85	JP (with English abstract)		YES	NO
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/BT/	AW	LIPP, S. et al., "A Comparison of Focused Ion Beam and Electron Beam Induced Deposition Processes", Microelectron. Reliab., Vol. 36, No. 11/12, pgs. 1779-1782, 1996.					
/BT/	AX	WARD, B.W. et al., "Repair of Photomasks with Focussed Ion Beams", SPIE, Vol. 537, pgs. 110-116, 1985.					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Binh Tran/					Date Considered 12/06/2007		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Laurent PAINFILING DATE
June 14, 2006

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/BT/	AA	4 751 169	06-14-88	BEHRINGER, Uwe et al.			
	AB						
	AC						
	AD						
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	AG						
	AH						
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	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/BT/	AO	0 200 333	12-10-86	EP		NO
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner /Binh Tran/

Date Considered 12/06/2007

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